

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): MEHRDAD NIKOONAHAD ET AL.
Title: SCANNING SYSTEM FOR INSPECTION ANOMALIES ON SURFACES
Application No.: 10/666,120 Filing Date: September 19, 2003
Examiner: Unknown Group Art Unit: 2877
Docket No.: TNCR.001US4 Conf. No.: 8430

Certificate of Mailing Under 37 CFR 1.8

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Signature

Tracey M. [Signature]

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicants call the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

Copies of the documents listed on the accompanying Form PTO-1449 that are not enclosed were previously submitted in Application(s) No. **09/954,287**, from which this Application claims an earlier effective filing date.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or

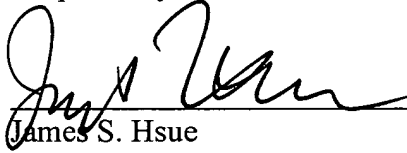
Attorney Docket No.: TNCR.001US4

Application No.: 10/666,120

(3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required. The Commissioner is authorized, however, to charge any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

Respectfully submitted,



James S. Hsue
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4-7-04

Date

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U.S. Department of Commerce, Patent and Trademark				Atty. Docket No.		Application No.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				TNCR.001US4		10/666,120	
				Applicant(s)		Conf. No.	
(Use several sheets if necessary)				Nikoonahad et al.		8430	
				Filing Date		Group	
				September 19, 2003		2877	

U.S. Patent Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	1	4,230,940	10/1980	Minami et al.			
	2	4,240,442	12/1980	Andresen et al.			
	3	4,676,637	6/1987	Uto et al.			
	4	4,889,998	12/1989	Hayano et al.			
	5	4,966,455	10/1990	Avni et al.			
	6	5,133,635	7/1992	Malin et al.			
	7	5,479,252	12/1995	Worster et al.			
	8	5,530,550	6/1996	Nikoonahad et al.			
	9	5,699,447	12/1997	Alumot et al.			
	10	5,767,962	6/1998	Suzuki et al.			

Foreign Patent Documents							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	11							
	12	0398781	11/1998	Europe				
	13	96-18093	6/1996	WIPO				

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
	14	"Imaging Systems: Detectors of the Past, Present, and Future," S. McGeorge, Spectroscopy, Vo. 2, No. \$, 1987
*	15	"Measurement of Hemispherical Directional Reflectance in the Infrared," J.T. Neu, SPIE Optical Scattering, Vol. 1995, 1993, pp. 101-120
*	16	"Discrete Sources Method for the Silicon Wafers Defect Discrimination," Yuri Eremin and N. Orlov, J. 12 th Annual Review of Progress in Applied Computational Electromagnetics, March 18-22, 1996, pp. 758-763
*	17	"Determination of COP Distribution After SC1 Cleaning By A Laser Particle Counter," T. Fujise et al., Optical Characterization Techniques for High-Performance Microelectronic Device Manufacturing III, SPIE Proc. Vol. 2877, October 16, 1998, pp. 16-25

Examiner	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

* US PTO did not receive these documents